

HiPerFET™ Power MOSFETs Q Class

N-Channel Enhancement Mode
Avalanche Rated
Low Q_g , High dv/dt

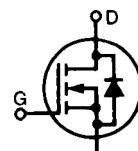
Preliminary data sheet

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	1000		V
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1 \text{ M}\Omega$	1000		V
V_{GS}	Continuous	± 20		V
V_{GSM}	Transient	± 30		V
I_{D25}	$T_c = 25^\circ\text{C}$	12		A
I_{DM}	$T_c = 25^\circ\text{C}$, pulse width limited by T_{JM}	48		A
I_{AR}	$T_c = 25^\circ\text{C}$	12		A
E_{AR}	$T_c = 25^\circ\text{C}$	30		mJ
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100 \text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 2 \Omega$	5		V/ns
P_D	$T_c = 25^\circ\text{C}$	300		W
T_J		-55 ... +150		$^\circ\text{C}$
T_{JM}		150		$^\circ\text{C}$
T_{stg}		-55 ... +150		$^\circ\text{C}$
T_L	1.6 mm (0.063 in) from case for 10 s	300		$^\circ\text{C}$
M_d	Mounting torque	1.13/10		Nm/lb.in.
Weight	TO-247 AD	6		g
	TO-268	4		g

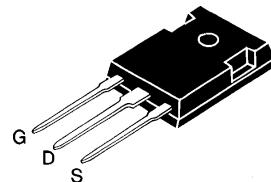
Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
V_{DSS}	$V_{GS} = 0 \text{ V}$, $I_D = 3 \text{ mA}$	1000		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 4 \text{ mA}$	2.5		5.5 V
I_{GSS}	$V_{GS} = \pm 20 \text{ V}_{DC}$, $V_{DS} = 0$			$\pm 100 \text{ nA}$
I_{DSS}	$V_{DS} = 0.8 \cdot V_{DSS}$ $V_{GS} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$		50 μA 1 mA
$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$, $I_D = 0.5 I_{D25}$ Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$			1.05 Ω

IXFH 12N100Q IXFT 12N100Q

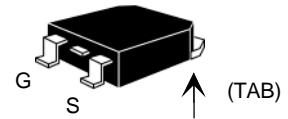
$V_{DSS} = 1000 \text{ V}$
 $I_{D25} = 12 \text{ A}$
 $R_{DS(on)} = 1.05 \Omega$
 $t_{rr} \leq 200 \text{ ns}$



TO-247 AD (IXFH)



TO-268 (D3) (IXFT)



G = Gate D = Drain
S = Source TAB = Drain

Features

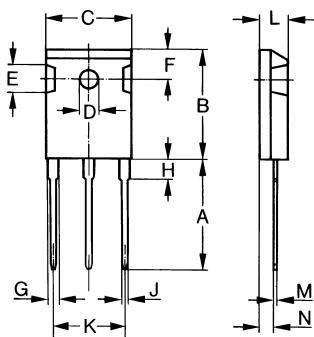
- IXYS advanced low Q_g process
- Low gate charge and capacitances
 - easier to drive
 - faster switching
- International standard packages
- Low $R_{DS(on)}$
- Unclamped Inductive Switching (UIS) rated
- Molding epoxies meet UL94 V-0 flammability classification

Advantages

- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values ($T_j = 25^\circ\text{C}$, unless otherwise specified)		
		min.	typ.	max.
g_{fs}	$V_{DS} = 15 \text{ V}; I_D = 0.5 \cdot I_{D25}$, pulse test	4	10	S
C_{iss}		2900		pF
C_{oss}		315		pF
C_{rss}		50		pF
$t_{d(on)}$		20		ns
t_r		23		ns
$t_{d(off)}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$, $R_G = 2 \Omega$ (External),	40		ns
t_f		15		ns
$Q_{g(on)}$		90		nC
Q_{gs}		30		nC
Q_{gd}		40		nC
R_{thJC}		0.42		K/W
R_{thCK}	(TO-247)	0.25		K/W

TO-247 AD (IXFH) Outline



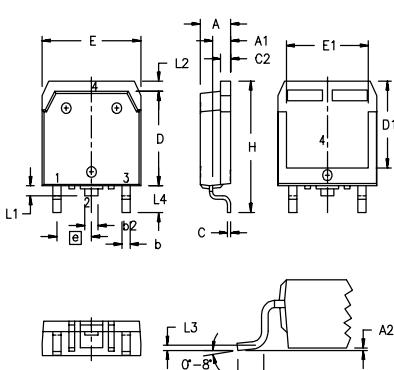
Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	19.81	20.32	0.780	0.800
B	20.80	21.46	0.819	0.845
C	15.75	16.26	0.610	0.640
D	3.55	3.65	0.140	0.144
E	4.32	5.49	0.170	0.216
F	5.4	6.2	0.212	0.244
G	1.65	2.13	0.065	0.084
H	-	4.5	-	0.177
J	1.0	1.4	0.040	0.055
K	10.8	11.0	0.426	0.433
L	4.7	5.3	0.185	0.209
M	0.4	0.8	0.016	0.031
N	1.5	2.49	0.087	0.102

Source-Drain Diode

Characteristic Values

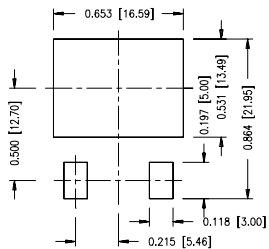
(T_j = 25°C, unless otherwise specified)

Symbol	Test Conditions	min.	typ.	max.
I _s	$V_{GS} = 0 \text{ V}$		12	A
I _{SM}	Repetitive; pulse width limited by T _{JM}		48	A
V _{SD}	$I_F = I_S, V_{GS} = 0 \text{ V}$, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %		1.3	V
t_{rr}	$I_F = I_S, -di/dt = 100 \text{ A}/\mu\text{s}, V_R = 100 \text{ V}$	200		ns
Q _{RM}		0.6		μC
I _{RM}		7		A

TO-268AA (D³ PAK)

Dim.	Millimeter Min.	Max.	Inches Min.	Max.
A	4.9	5.1	.193	.201
A ₁	2.7	2.9	.106	.114
A ₂	.02	.25	.001	.010
b	1.15	1.45	.045	.057
b ₂	1.9	2.1	.75	.83
C	.4	.65	.016	.026
D	13.80	14.00	.543	.551
E	15.85	16.05	.624	.632
E ₁	13.3	13.6	.524	.535
e	5.45 BSC		.215 BSC	
H	18.70	19.10	.736	.752
L	2.40	2.70	.094	.106
L1	1.20	1.40	.047	.055
L2	1.00	1.15	.039	.045
L3	0.25 BSC		.010 BSC	
L4	3.80	4.10	.150	.161

Min. Recommended Footprint



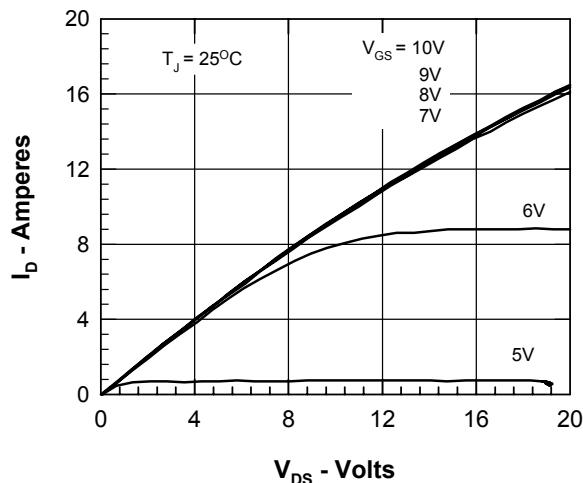


Figure 1. Output Characteristics at 25°C

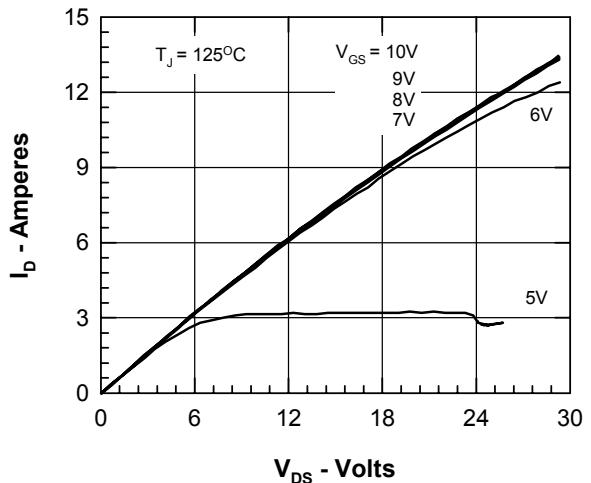


Figure 2. Output Characteristics at 125°C

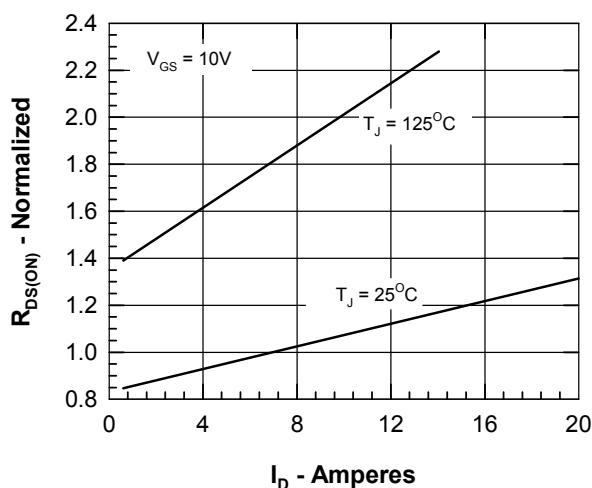


Figure 3. $R_{DS(on)}$ normalized to value at $I_D = 12A$

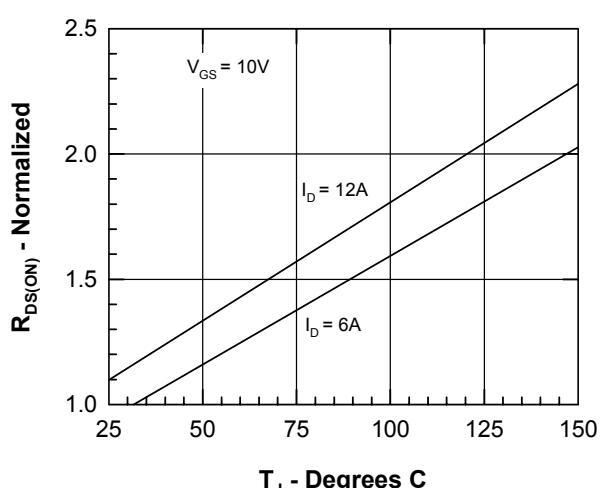


Figure 4. $R_{DS(on)}$ normalized to value at $I_D = 12A$

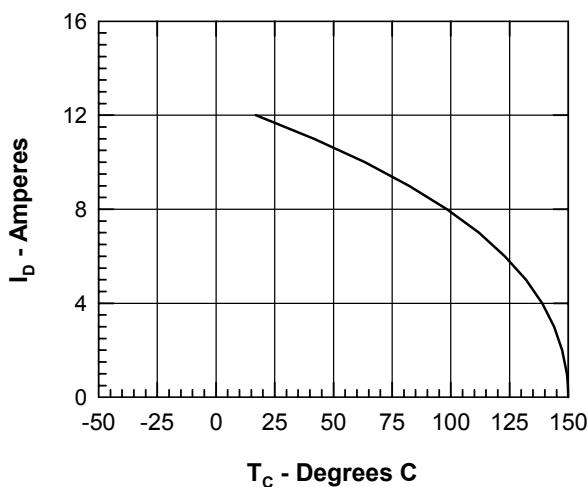


Figure 5. Drain Current vs. Case Temperature

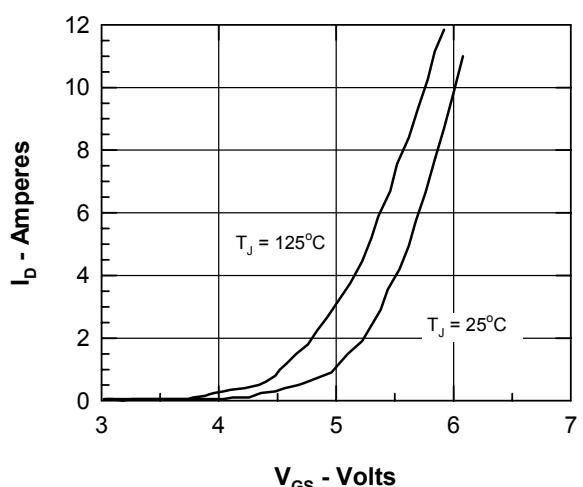


Figure 6. Admittance Curves

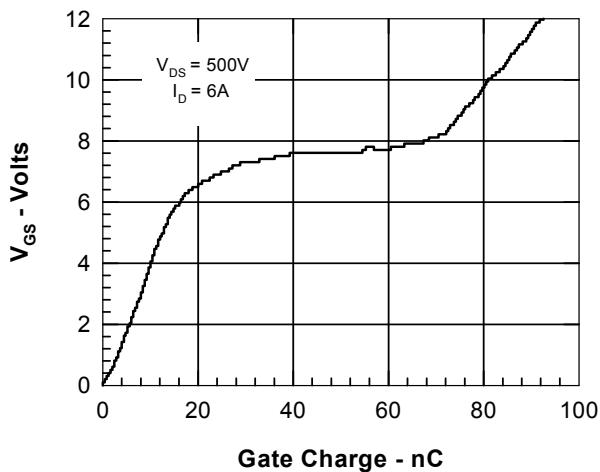


Figure 7. Gate Charge

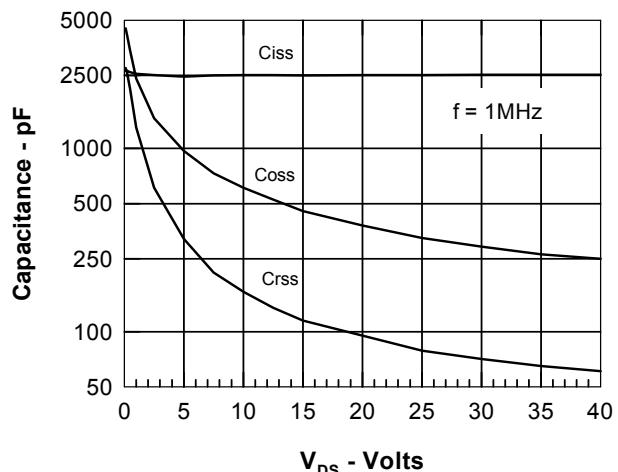


Figure 8. Capacitance Curves

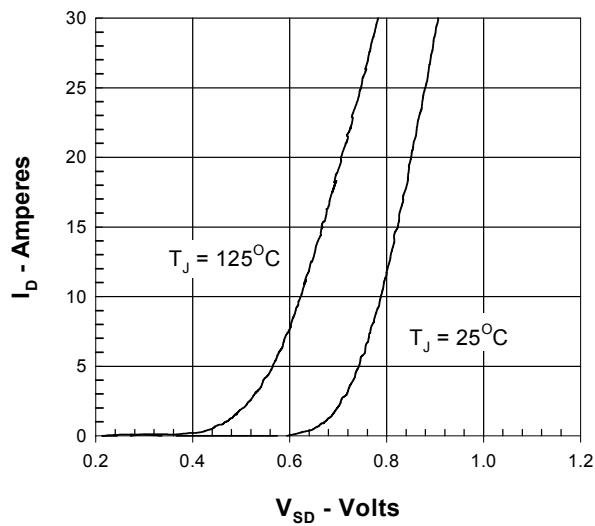


Figure 9. Source Current vs. Source to Drain Voltage

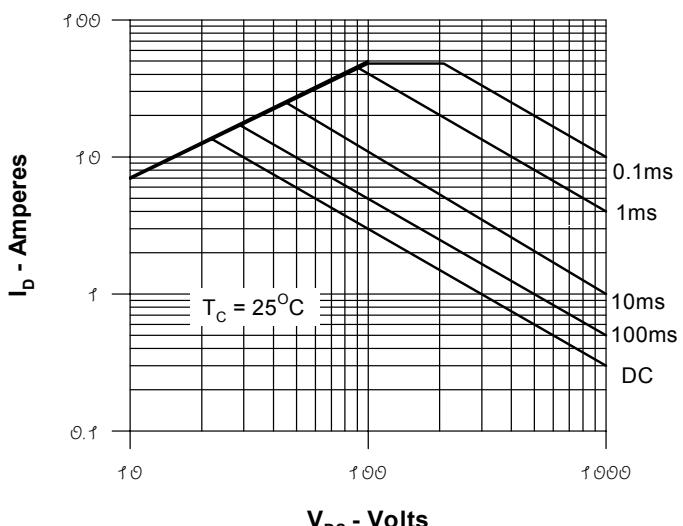


Figure 10. Forward Bias Safe Operating Area

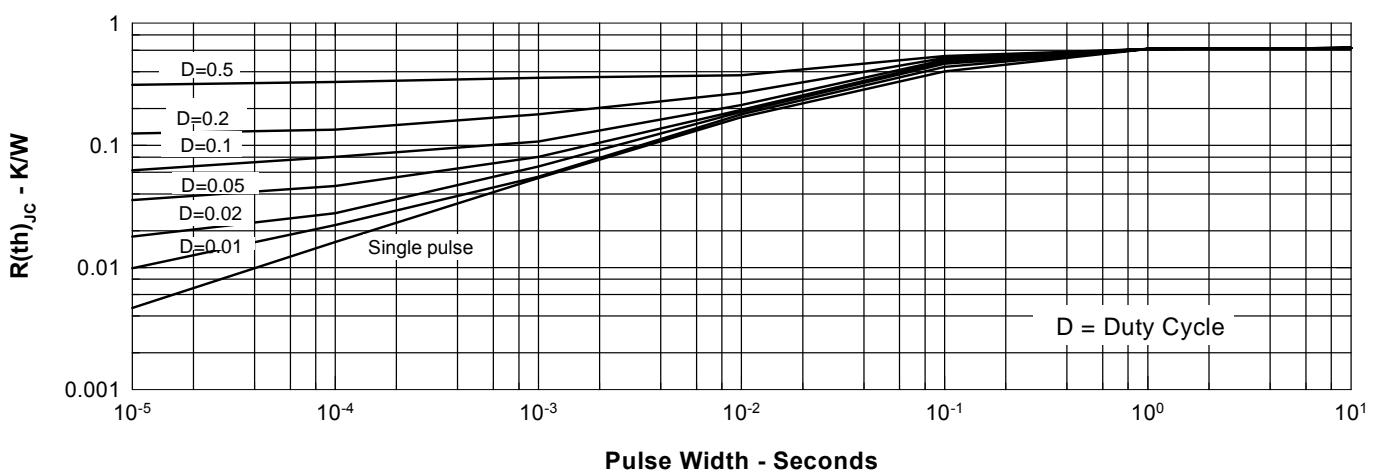


Figure 11. Transient Thermal Resistance